

Automatic Test Pattern Generation - IV

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EE 709: Testing & Verification of VLSI Circuits

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ATPG - Algorithmic

❖ Path Sensitization Method

- Fault Sensitization
- Fault Propagation
- Line Justification

❖ Path Sensitization Algorithms

- D- Algorithm (Roth)
- PODEM (P. Goel)
- FAN (Fujiwara)
- SOCRATES (Schultz)
- SPIRIT (Emil & Fujiwara)

Common Concept

- ❖ Fault Activation problem \rightarrow a LJ Problem
- ❖ The Fault Propagation problem \rightarrow
 1. Select a FP path to PO \rightarrow Decision
 2. Once the path is selected \rightarrow a set of LJ problems
- ❖ The LJ Problems \rightarrow Decisions or Implications



To justify $c = 1 \rightarrow a = 1, b = 1$ (Implication)

To justify $c = 0 \rightarrow a = 0$ or $b = 0$ (Decision)

- ❖ Incorrect decision \rightarrow Backtrack \rightarrow Another decision

FANout oriented test generation

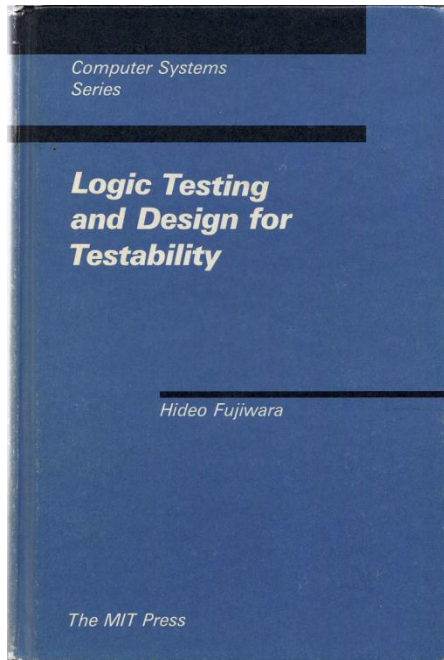
FAN

(Fujiwara & Shimono, 1983)

Prof. Hideo Fujiwara



- Prof. Fujiwara is Eminent Researcher and Academician in VLSI Testing
- Many contributions to VLSI Testing
- Co-founder of ATS and WRTL
- Special Workshop was organized in his honour with 20th IEEE ATS 2011



TG Algorithms

Objective

- ❖ TG time reduction
 - Reduce number of backtracks
 - Find out the non-existence of solution as soon as possible
 - Branch and bound

FAN Algorithm

❖ New concepts:

- Immediate assignment of *uniquely-determined signals*
- *Unique sensitization*
- Stop Backtrace at *head lines*
- *Multiple Backtrace*

FAN Algorithm

Strategies:

Strategy1:

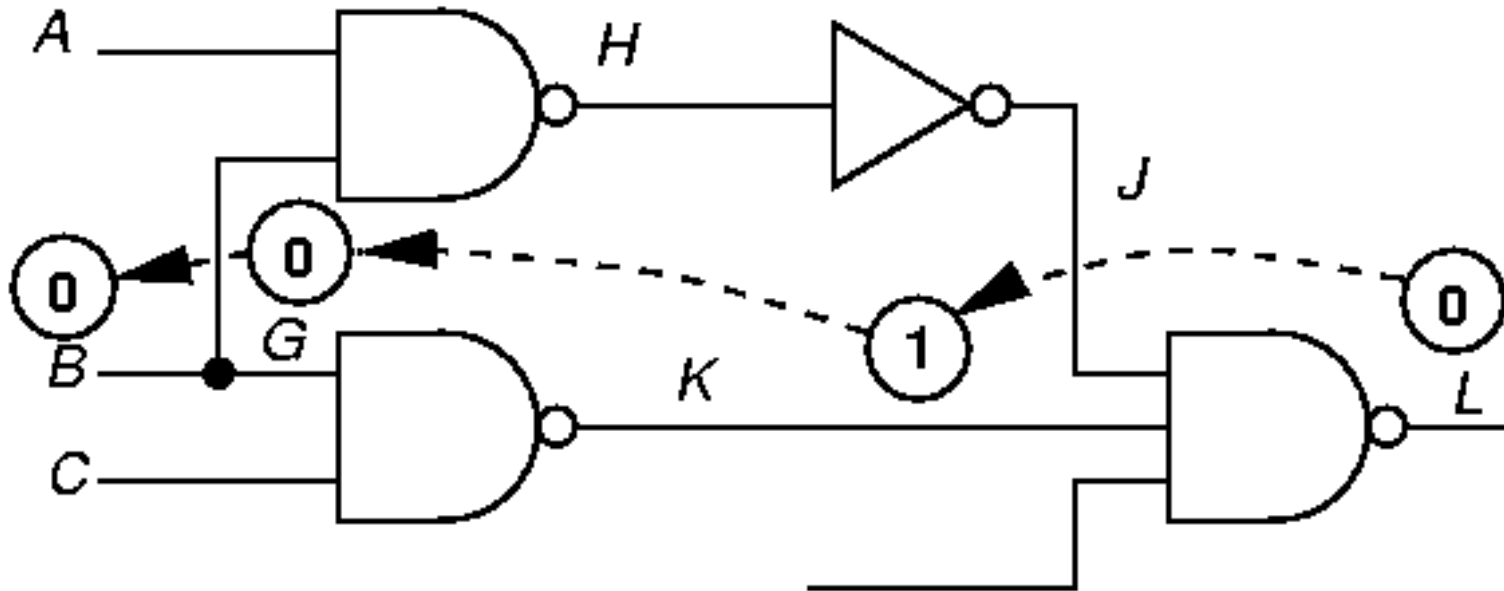
- In step of the algorithm determine as many signal values as possible

❖ Implication

Strategy 2:

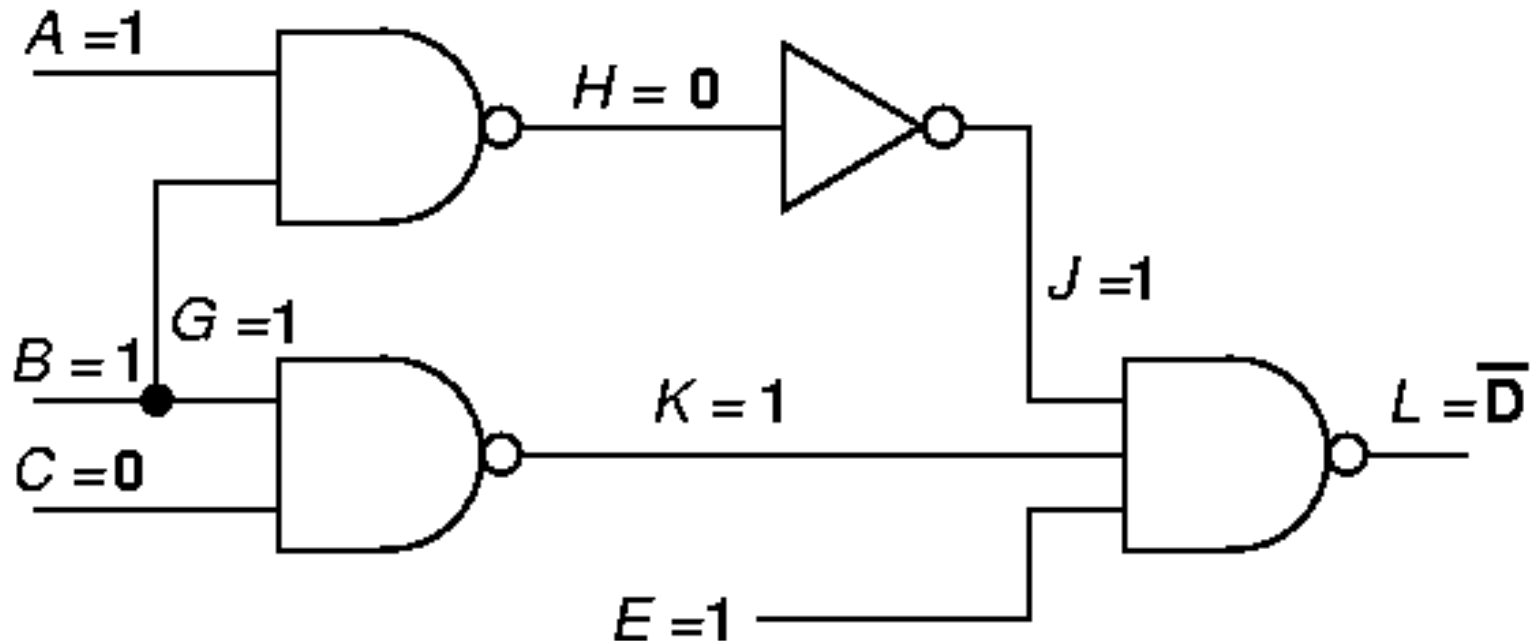
- Assign faulty signal D or D' that is uniquely determined or implied by the fault in question

PODEM Fails to Determine Unique Signals



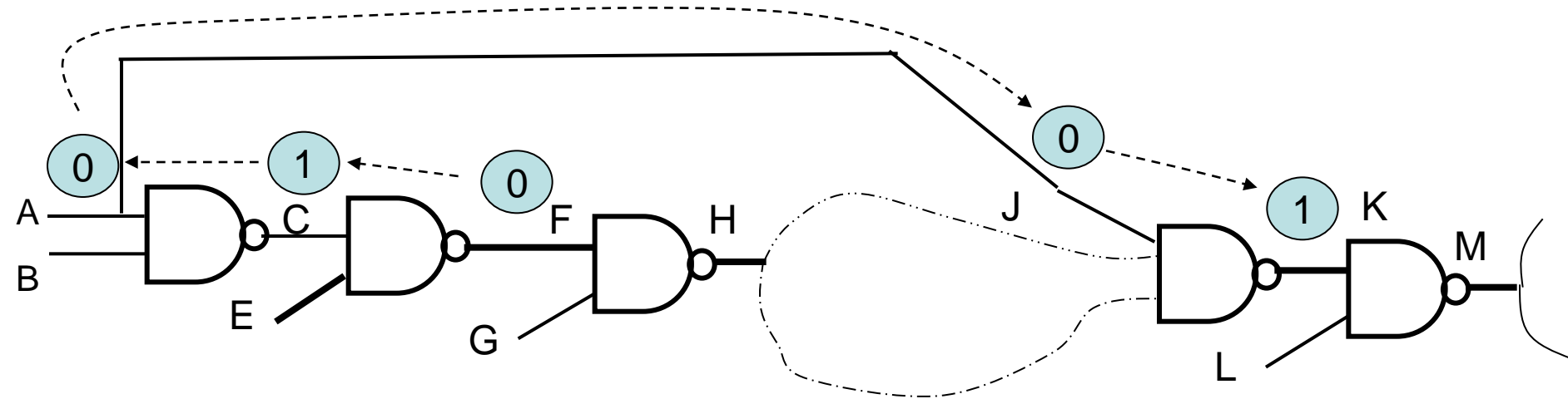
- **Backtracing operation fails to set all 3 inputs of gate *L* to 1**
 - **Causes unnecessary search**

FAN -- Early Determination of Unique Signals



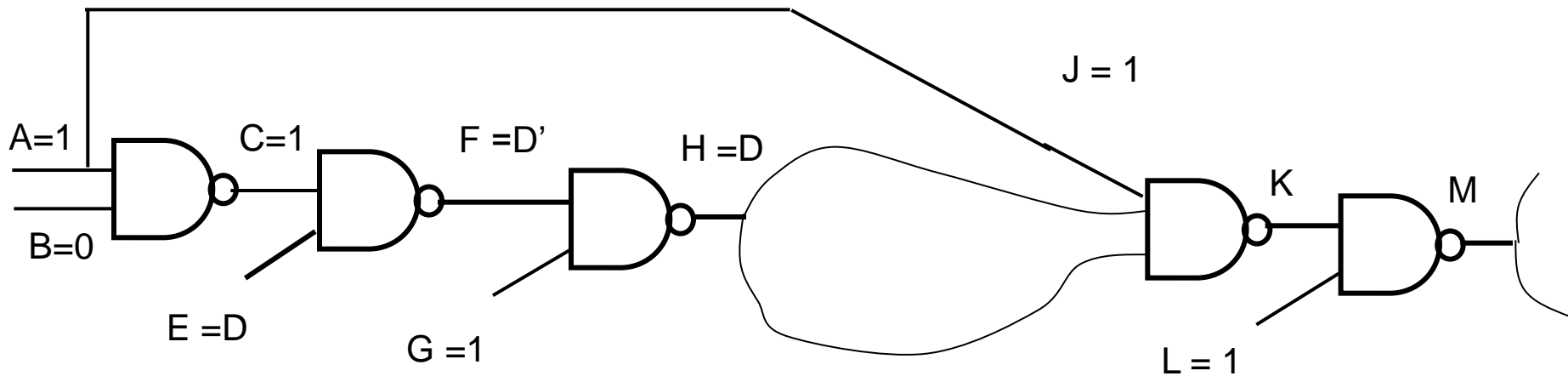
- **Determine all unique signals implied by current decisions immediately**
 - **Avoids unnecessary search**

PODEM Makes Unwise Signal Assignments



n Blocks fault propagation due to assignment $J = 0$

FAN – Unique sensitization



- n FAN immediately sets necessary signals to propagate fault

Unique sensitization and implication

Partial sensitization, which uniquely determined, is called unique sensitization

FAN Algorithm

Strategies:

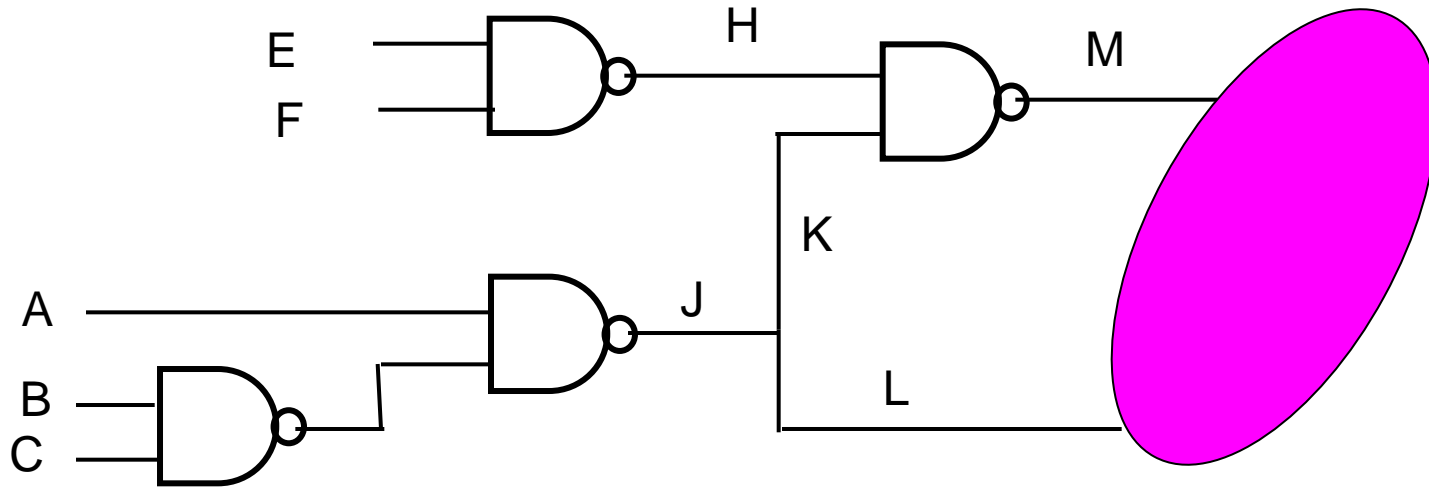
Strategy 3:

- When the D-frontier consists of a single gate, apply a **unique sensitization**

Strategy 4:

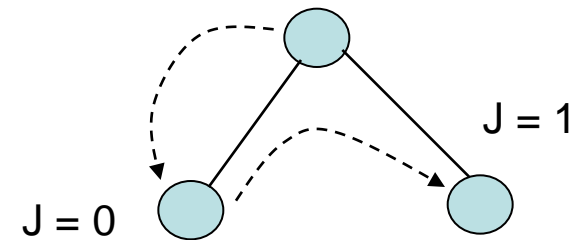
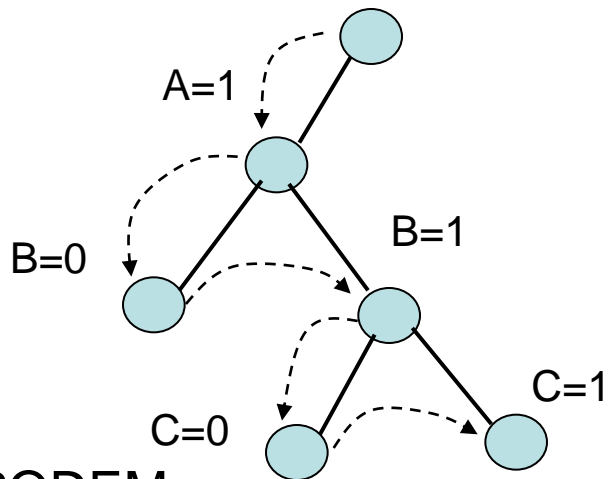
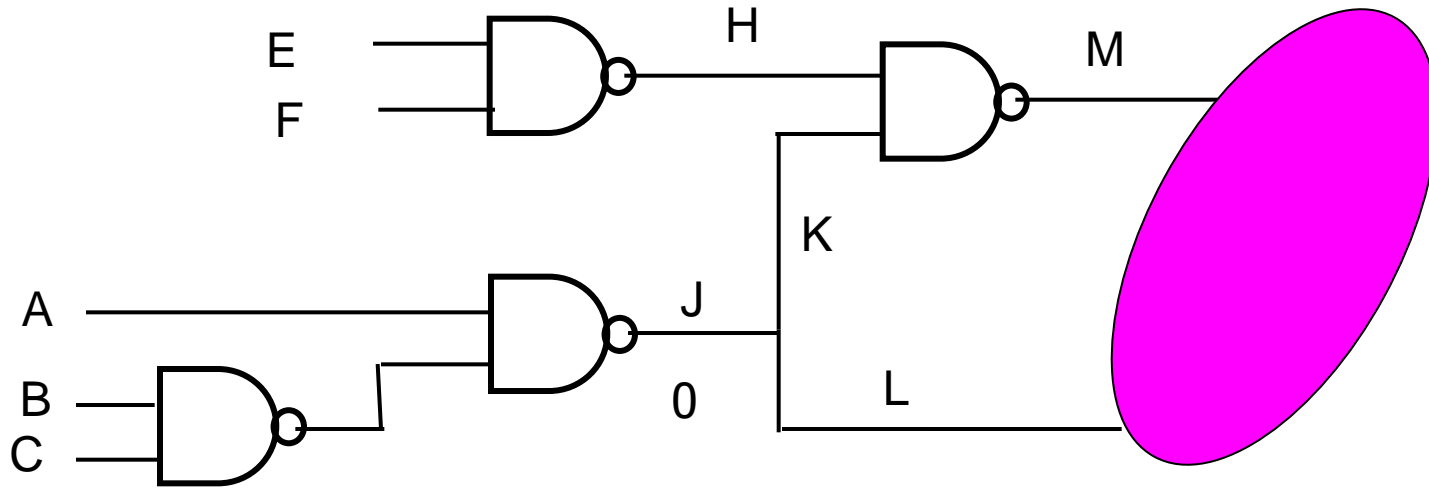
- Stop the backtrace at a *headline*, and postpone the line justification for the *headline* to later

Headlines



- When a line L is reachable from a fanout point, L is said to be **bound**
- A signal line that is not bound is said to be **free**
- When a line is adjacent to some bound line, it is said to be **head line**

Decision Trees



Backtracking at Head-lines

PODEM

FAN Algorithm

Strategies:

Strategy 5:

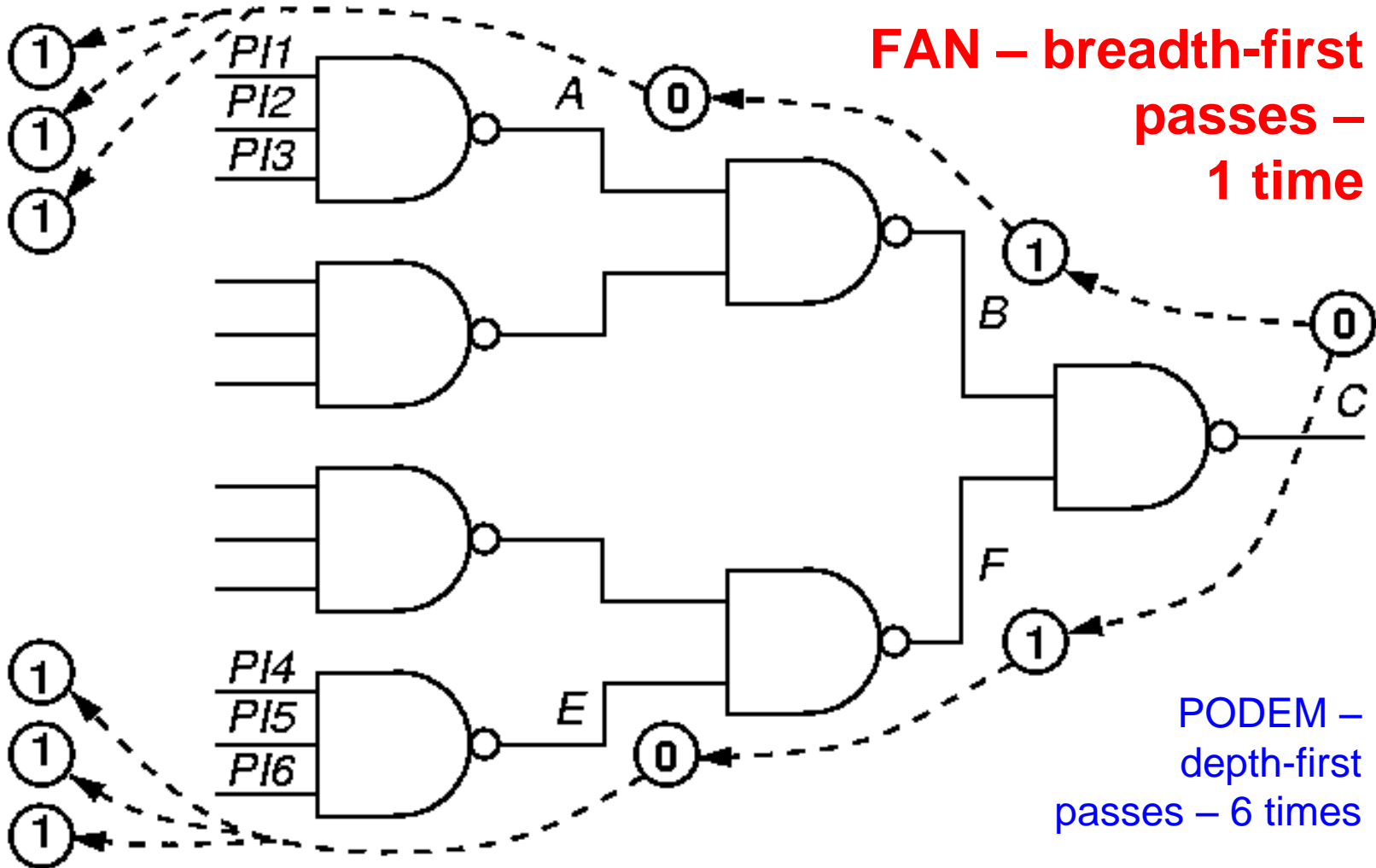
- Multiple backtracing (concurrent backtracing of more than one path) is more efficient than backtracing along a single path

Objective for multiple backtrace

❖ Triplet

❖ $(s, n_0(s), n_1(s))$

Multiple Backtrace



FAN Algorithm

Objective for multiple backtrace

❖ Triplet

❖ $(s, n_0(s), n_1(s))$

AND gate

❖ Let X be the easiest to set to 0 input

$$n_0(X) = n_0(Y), \quad n_1(X) = n_1(Y)$$

For other inputs X_i

$$n_0(X_i) = 0, \quad n_1(X_i) = n_1(Y)$$

OR gate

Let X be the easiest to set to 1 input

$$n_0(X) = n_0(Y), \quad n_1(X) = n_1(Y)$$

For other inputs X_i

$$n_0(X_i) = n_0(Y), \quad n_1(X_i) = 0$$

FAN Algorithm

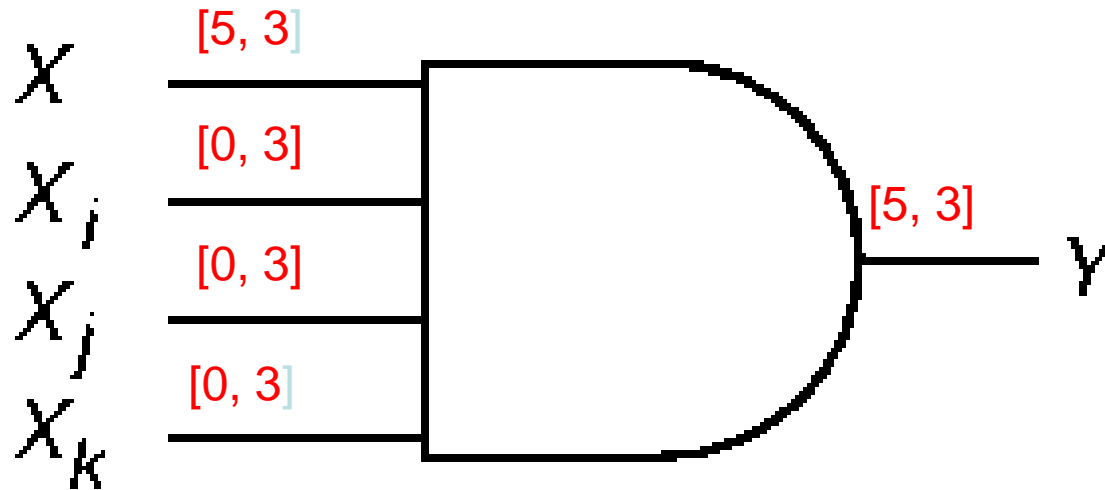
NOT gate

$$n_0(X) = n_1(Y), \quad n_1(X) = n_0(Y)$$

Fanout points

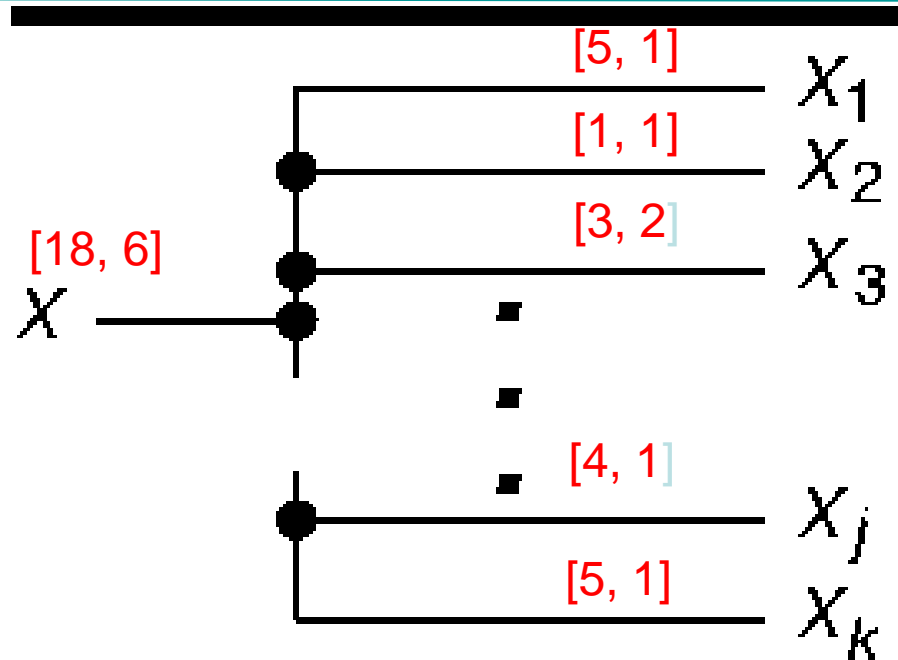
$$n_0(X) = \sum n_0(X_i), \quad n_1(X) = \sum n_1(X_i)$$

AND Gate Vote Propagation



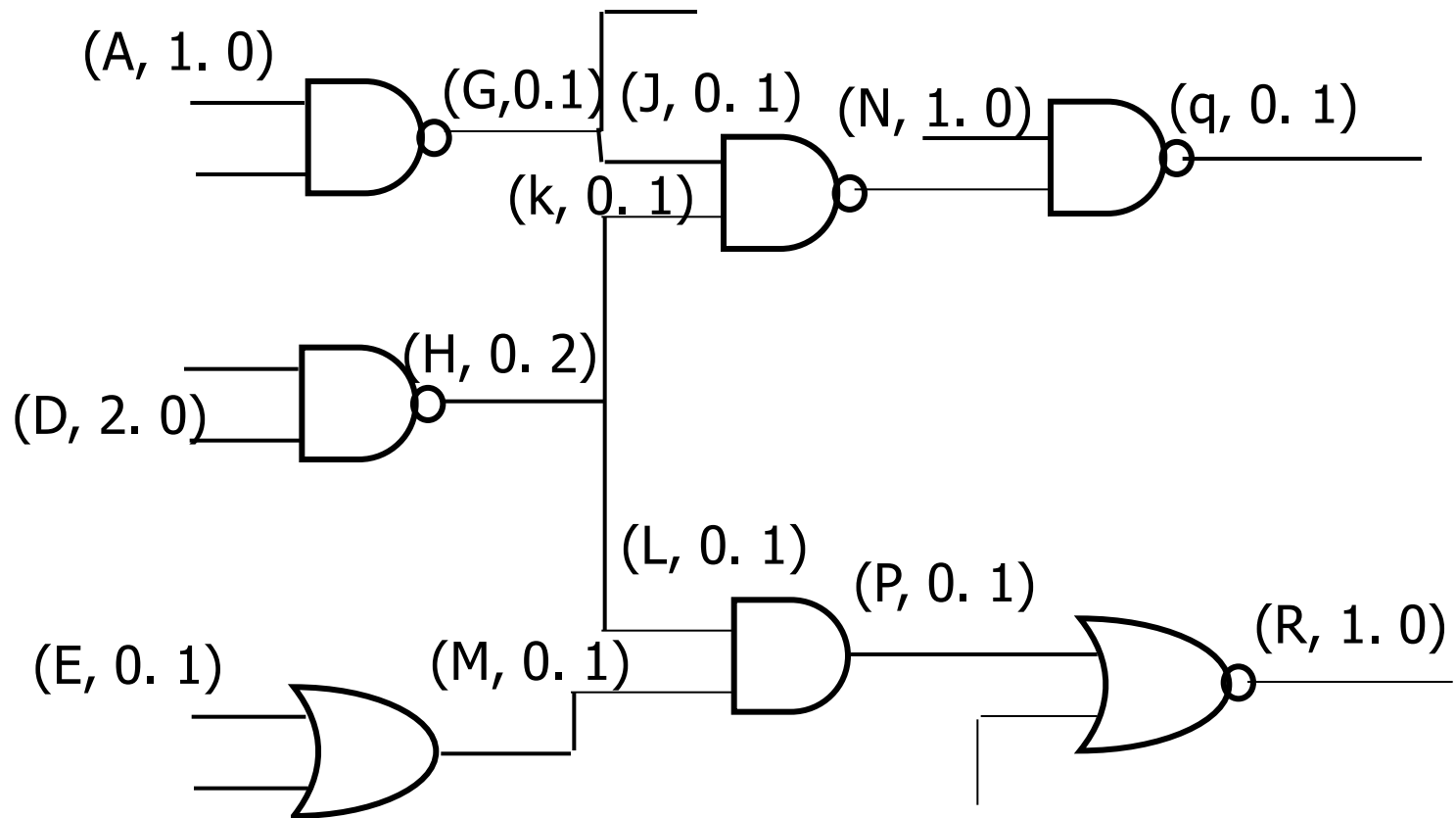
- **AND Gate**
 - **Easiest-to-control Input –**
 - # 0's = OUTPUT # 0's
 - # 1's = OUTPUT # 1's
 - **All other inputs --**
 - # 0's = 0
 - # 1's = OUTPUT # 1's

Multiple Backtrace Fanout Stem Voting



- Fanout Stem --
 - # 0's = Σ Branch # 0's,
 - # 1's = Σ Branch # 1's

FAN



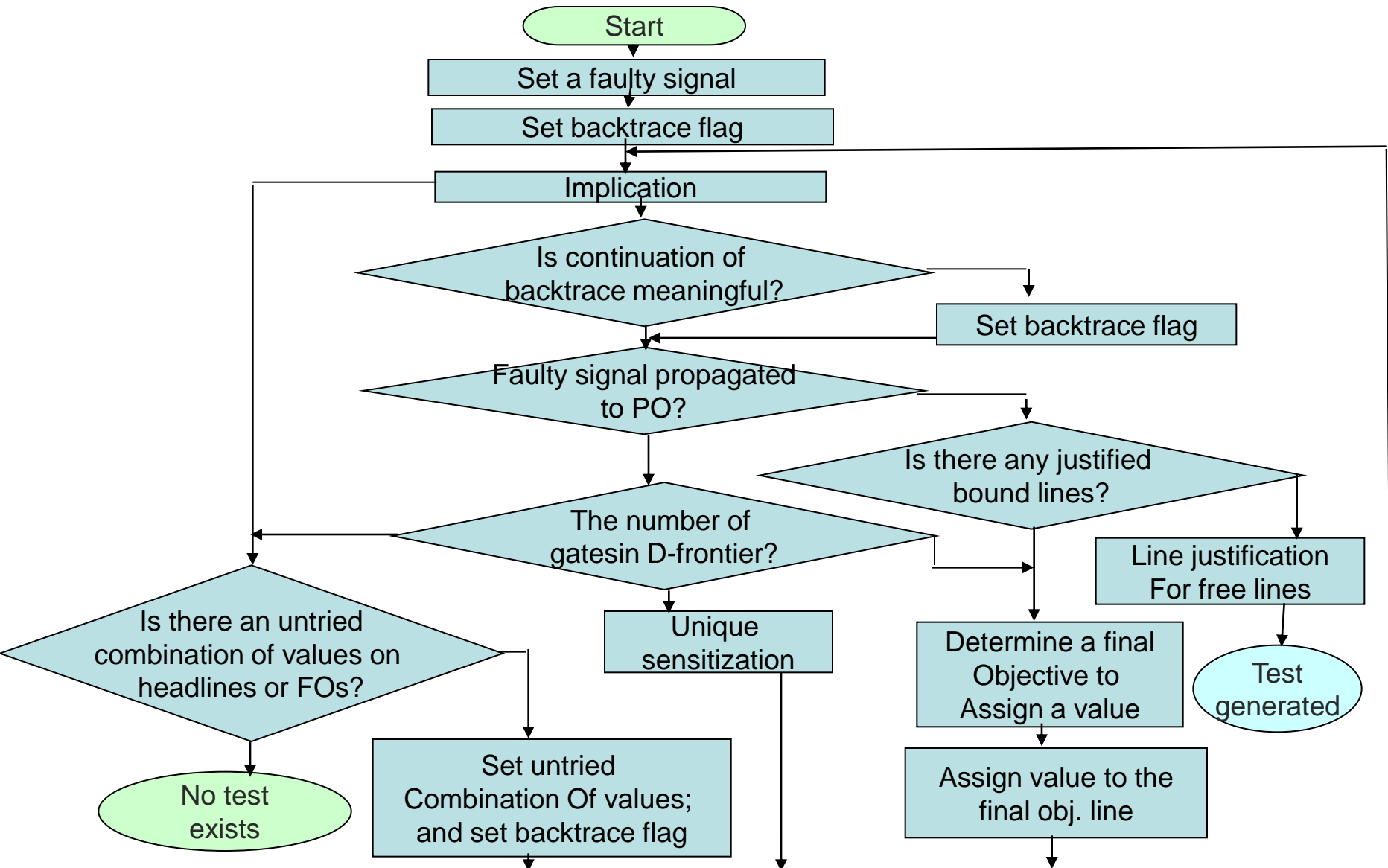
FAN Algorithm

Strategies:

Strategy 6:

- In the multiple backtrace, if an objective at a fanout point p has a contradictory requirement, that is, if both $n_0(p)$ and $n_1(p)$ are non-zero, stop backtrace so as to assign a binary value to the fanout point.

FAN - Algorithm



Static and Dynamic Compaction of Sequences

- **Static compaction**

- ATPG should leave unassigned inputs as X
- Two patterns *compatible* – if no conflicting values for any PI
- Combine two tests t_a and t_b into one test $t_{ab} = t_a \cap t_b$ using D-intersection
- Detects union of faults detected by t_a & t_b

- **Dynamic compaction**

- Process every partially-done ATPG vector immediately
- Assign 0 or 1 to PIs to test additional faults

Compaction Example

- $t_1 = 0\ 1\ X$ $t_2 = 0\ X\ 1$
 $t_3 = 0\ X\ 0$ $t_4 = X\ 0\ 1$

- **Combine t_1 and t_3 , then t_2 and t_4**

- **Obtain:**

$$- t_{13} = 0\ 1\ 0 \qquad t_{24} = 0\ 0\ 1$$

- ***Test Length* shortened from 4 to 2**

Thank You

